

Search Notes

Application/Control No.

10/501,917

Examiner

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Applicant(s)/Patent under
Reexamination

KATSUNUMA, TAKAYUKI

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	711	10/25/2006	BT
438	713	10/25/2006	BT
438	728	10/25/2006	BT
438	743	10/25/2006	BT

INTERFERENCE SEARCHED

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438	728	10/25/2006	BT
438/743		10/25/2006	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	10/25/2006	BT
438/706 text search only	10/25/2006	BT